

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HAN ET AL.	
		Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,813,592	09-1998	Midling et al.	228/112.1
*	B	US-6,726,084	04-2004	Duncan, Jr., Frank Gordon	228/112.1
*	C	US-2005/0035179	02-2005	Forrest et al.	228/112.1
*	D	US-6,585,148	07-2003	Aono et al.	228/112.1
*	E	US-6,676,004	01-2004	Trapp et al.	228/2.1
*	F	US-6,237,829	05-2001	Aota et al.	228/2.1
*	G	US-6,199,745	03-2001	Campbell et al.	228/112.1
*	H	US-6,029,879	02-2000	Cocks, Elijah E.	228/2.1
*	I	US-2003/0042293	03-2003	Ezumi et al.	228/112.1
	J	US-2002/0179682	12-2002	Schilling et al.	228/112.1
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-2001-321965-A	11-2001	Japan	Tomizawa et al.	
*	O	GB 2306366 A	05-1997	UK	Thomas et al.	
	P	JP-2003-181655-A	07-2003	Japan	Tanaka et al.	
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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